BLP8G20S-80P

Power LDMOS transistor

Rev. 2 — 13 October 2014

Product data sheet

1. Product profile

1.1 General description

80~W~LDMOS transistor for base station applications at frequencies from 1800~MHz to 2200~MHz.

Table 1. Typical performance

Typical RF performance per section at $T_{\rm case}$ = 25 °C in a common Doherty demo board.

Test signal	f	I _{Dq}	V _{DS}	P _{L(AV)}	Gp	ηр	ACPR
	(MHz)	(mA)	(V)	(W)	(dB)	(%)	(dBc)
2-carrier W-CDMA	1805 to 1880	300	28	14.2	17	47	-30 <u>[1]</u>
	1880 to 1920	300	28	14.2	16.8	46	-30 <u>[1]</u>
	2110 to 2170	300	28	14.2	16	43	-30 [<u>1]</u>

^[1] Test signal: 3GPP test model 1; 64 DPCH; PAR = 8.4 dB at 0.01 % probability on CCDF; carrier spacing = 5 MHz.

1.2 Features and benefits

- Designed for broadband operation (1800 MHz to 2200 MHz)
- Excellent ruggedness
- High efficiency
- Excellent thermal stability
- Internally matched for ease of use
- High power gain
- Integrated ESD protection
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)

1.3 Applications

■ RF power amplifiers for base station and multi-carrier applications in the 1800 MHz to 2200 MHz frequency range



2. Pinning information

Table 2. Pinning

Pin	Description	Simplified outline	Graphic symbol
1	gate 2		,
2	gate 1	4 3	4
3	drain 1		
4	drain 2	pin 1 index	Y
5	source	[1]	
			3 aaa-003574

^[1] Connected to flange.

3. Ordering information

Table 3. Ordering information

Type number	Package	Package			
	Name	Description	Version		
BLP8G20S-80P	HSOP4F	plastic, heatsink small outline package; 4 leads (flat)	SOT1223-1		

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage		-	65	V
V_{GS}	gate-source voltage		-0.5	+13	V
T _{stg}	storage temperature		-65	+150	°C
Tj	junction temperature	[1]	-	225	°C

^[1] Continuous use at maximum temperature will affect the reliability, for details refer to the on-line MTF

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Тур	Unit
R _{th(j-case)}	thermal resistance from junction to case	$T_{case} = 80 ^{\circ}C; P_{L} = 10 W$	0.85	K/W

6. Characteristics

Table 6. DC characteristics

 $T_i = 25$ °C per section, unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{(BR)DSS}	drain-source breakdown voltage	$V_{GS} = 0 \text{ V}; I_D = 0.5 \text{ mA}$	65	-	-	V
V _{GS(th)}	gate-source threshold voltage	$V_{DS} = 10 \text{ V}; I_D = 47 \text{ mA}$	1.55	1.9	2.25	V
I _{DSS}	drain leakage current	V _{GS} = 0 V; V _{DS} = 28 V	-	-	1.2	μΑ
I _{DSX}	drain cut-off current	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $V_{DS} = 10 \text{ V}$	-	8.5	-	А
I _{GSS}	gate leakage current	V _{GS} = 11 V; V _{DS} = 0 V	-	-	120	nA
9 _{fs}	forward transconductance	$V_{DS} = 10 \text{ V}; I_D = 47 \text{ mA}$	-	0.41	-	S
R _{DS(on)}	drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $I_D = 1.645 \text{ A}$	-	0.32	-	Ω

Table 7. RF characteristics

Test signal: 2-carrier W-CDMA; PAR = 8.4 dB at 0.01 % probability on CCDF; carrier spacing = 5 MHz; 3GPP test model 1; 64 DPCH; f_1 = 1882.5 MHz; f_2 = 1887.5 MHz; f_3 = 1912.5 MHz; f_4 = 1917.5 MHz; RF performance per section at $V_{\rm DS}$ = 28 V; $I_{\rm Dq}$ = 300 mA; $T_{\rm case}$ = 25 °C; unless otherwise specified; in a class-AB production test circuit.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Gp	power gain	$P_{L(AV)} = 10 \text{ W}$	16.5	17.5	-	dB
η_{D}	drain efficiency	$P_{L(AV)} = 10 \text{ W}$	29	33	-	%
RLin	input return loss	$P_{L(AV)} = 10 \text{ W}$	-	-10	-7	dB
ACPR	adjacent channel power ratio	$P_{L(AV)} = 10 W$	-	-32	-28	dBc

7. Test information

7.1 Ruggedness in class-AB operation

The BLP8G20S-80P is capable of withstanding a load mismatch corresponding to a VSWR = 10 : 1 through all phases under the following conditions: V_{DS} = 28 V; I_{Dq} = 300 mA; P_{L} = 40 W (CW); f = 1805 MHz.

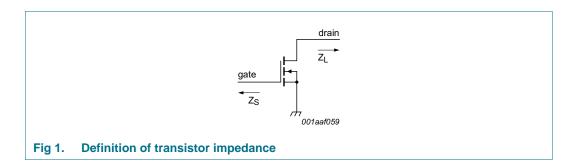
7.2 Impedance information

Table 8. Typical impedance

Measured load-pull data.

f	Z _S [1]	Z _L [1]
(MHz)	(Ω)	(Ω)
1880	2.3 – 14.0j	4.5 – 10.5j
1920	3.0 – 15.7j	4.1 – 10.6j

[1] Z_S and Z_L defined in Figure 1.



7.3 Test circuit

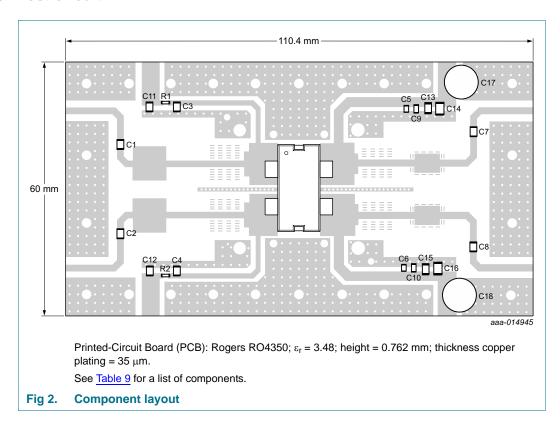


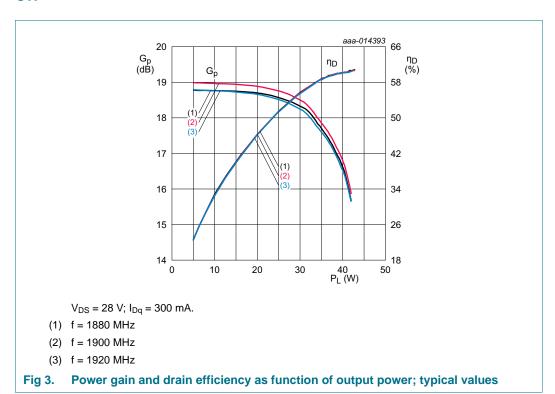
Table 9. List of components

See Figure 2 for component layout.

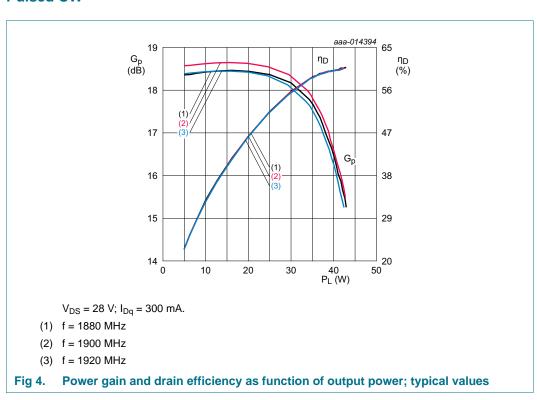
Component	Description	Value	Remarks
C1, C2, C3, C4, C5, C6, C7, C8	multilayer ceramic chip capacitor	11 pF	ATC 600F series or capacitor of same quality
C9, C10	multilayer ceramic chip capacitor	1 μF, 50 V	Murata or capacitor of same quality
C11, C12, C13, C14, C15, C16	multilayer ceramic chip capacitor	4.7 μF, 50 V	Murata or capacitor of same quality
C17, C18	multilayer ceramic chip capacitor	2200 μF, 50 V	
R1, R2	SMD resistor	9.1 Ω	SMD 0805

7.4 Graphical data

7.4.1 CW

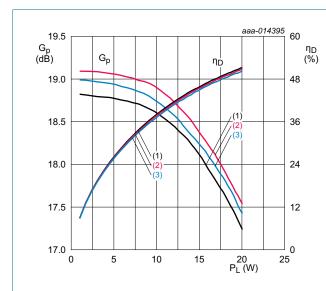


7.4.2 Pulsed CW



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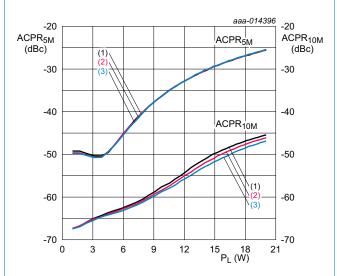
7.4.3 1-Carrier W-CDMA



 $V_{DS} = 28 \text{ V}; I_{Dq} = 300 \text{ mA}.$

- (1) f = 1880 MHz
- (2) f = 1900 MHz
- (3) f = 1920 MHz

Fig 5. Power gain and drain efficiency as function of output power; typical values

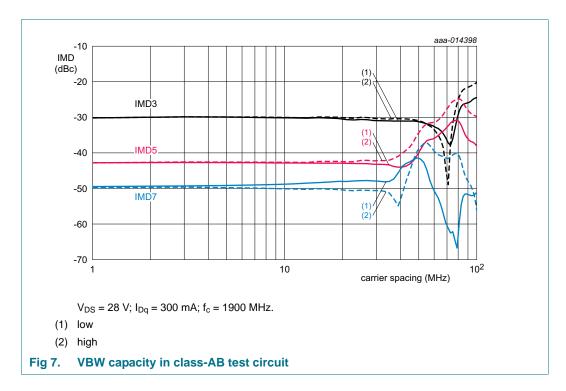


 $V_{DS} = 28 \text{ V}; I_{Dq} = 300 \text{ mA}.$

- (1) f = 1880 MHz
- (2) f = 1900 MHz
- (3) f = 1920 MHz

Fig 6. Adjacent channel power ratio (5 MHz) and adjacent channel power ration (10 MHz) as function of output power; typical values

7.4.4 VBW



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8. Package outline

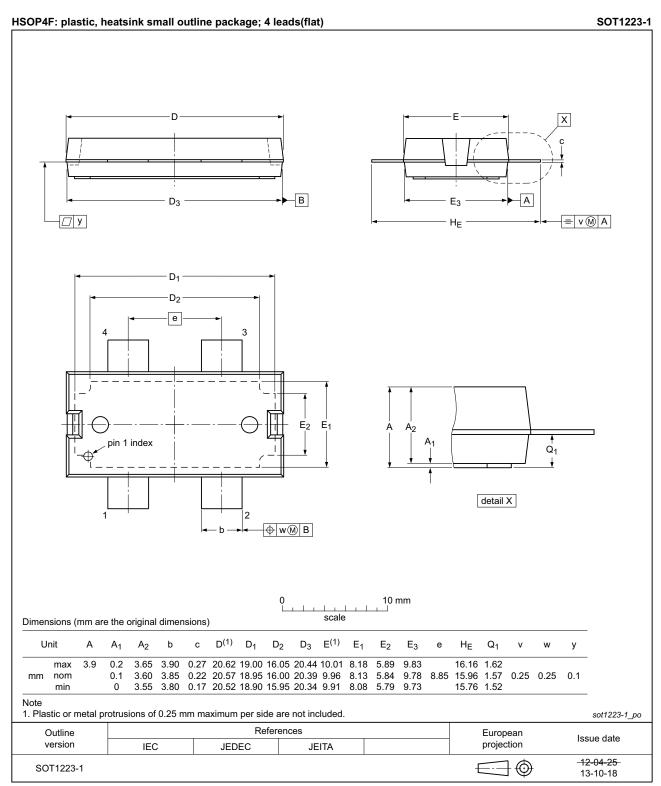


Fig 8. Package outline SOT1223-1 (HSOP4F)

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9. Handling information

CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Observe precautions for handling electrostatic sensitive devices.

Such precautions are described in the ANSI/ESD S20.20, IEC/ST 61340-5, JESD625-A or equivalent standards.

10. Abbreviations

Table 10. Abbreviations

Acronym	Description
3GPP	3rd Generation Partnership Project
CCDF	Complementary Cumulative Distribution Function
CW	Continuous Wave
DPCH	Dedicated Physical CHannel
ESD	ElectroStatic Discharge
LDMOS	Laterally Diffused Metal Oxide Semiconductor
MTF	Median Time to Failure
PAR	Peak-to-Average Ratio
SMD	Surface Mounted Device
VBW	Video BandWidth
VSWR	Voltage Standing Wave Ratio
W-CDMA	Wideband Code Division Multiple Access

11. Revision history

Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes	
BLP8G20S-80P v.2	20141013	Product data sheet	-	BLP8G20S-80P v.1	
Modifications	• Table 1 on p	Table 1 on page 1: table updated			
	Section 1.2	• Section 1.2 on page 1: changed '1880 MHz to 1920 MHz' to '1800 MHz to 2200 MHz'			
	 Section 1.3 on page 1: changed '1880 MHz to 1920 MHz' to '1800 MHz to 2200 MHz' 			00 MHz to 2200 MHz'	
	<u>Table 5 on page 2</u> : table updated				
	<u>Table 6 on page 3</u> : table updated				
	• <u>Table 7 on page 3</u> : table updated				
	Section 7 on page 3: section added				
BLP8G20S-80P v.1	20140630	Objective data sheet	-	-	

12. Legal information

12.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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- [2] The term 'short data sheet' is explained in section "Definitions"
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